



HY11P32
Datasheet
8-Bit RISC-like Mixed Signal Microcontroller
Embedded 4x12 LCD Driver
18-Bit Σ ADC

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1. 特點

- 8 位元精簡指令集，共有 46 個指令
- 2.2V to 3.6V 工作電壓範圍，-40~85°C 工作溫度範圍。
- 內部高精度 RC 震盪器，4 種 CPU 工作時脈切換選擇，可讓使用者達到最佳省電規劃。
 - 運行模式 300uA@2MHz
 - 待機模式 3uA@28KHz
 - 休眠模式 1uA
- 2KWord OTP (One Time Programmable) Type 程式記憶體，128Byte 資料記憶體
- Brownout detector 及 Watch dog Timer，可防止 CPU 進入死機模式。
- 18bit 全差動輸入 $\Sigma\Delta$ ADC 類比數位轉換器
 - 內置 PGA (Programmable Gain Amplifier) 及可有 1/4、1/2、1、.....128 倍 10 種輸入信號放大倍率選擇
 - 內置輸入零點調整，可針對不同應用增加其量測範圍
- 1.0V 的內部類比電路共地電壓源，具有 Push-Pull 驅動能力，可提供傳感器驅動電壓
- LVD 低電壓檢測功能具 14 段檢測電壓設置與外部輸入電壓檢測功能
- 類比電壓源 VDDA 具 10mA 穩壓電壓源輸出能力
- 4x12 LCD 液晶驅動器
 - 1/4 Duty、1/3 Bias
 - 內建 Charge Pump 穩壓線路，可提供 4 種 LCD 偏壓
- 8-bit Timer A
- Build-In EPROM (BIE)
- Support 6 stack level

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2. 引腳定義

2.1 LQFP44 引腳圖

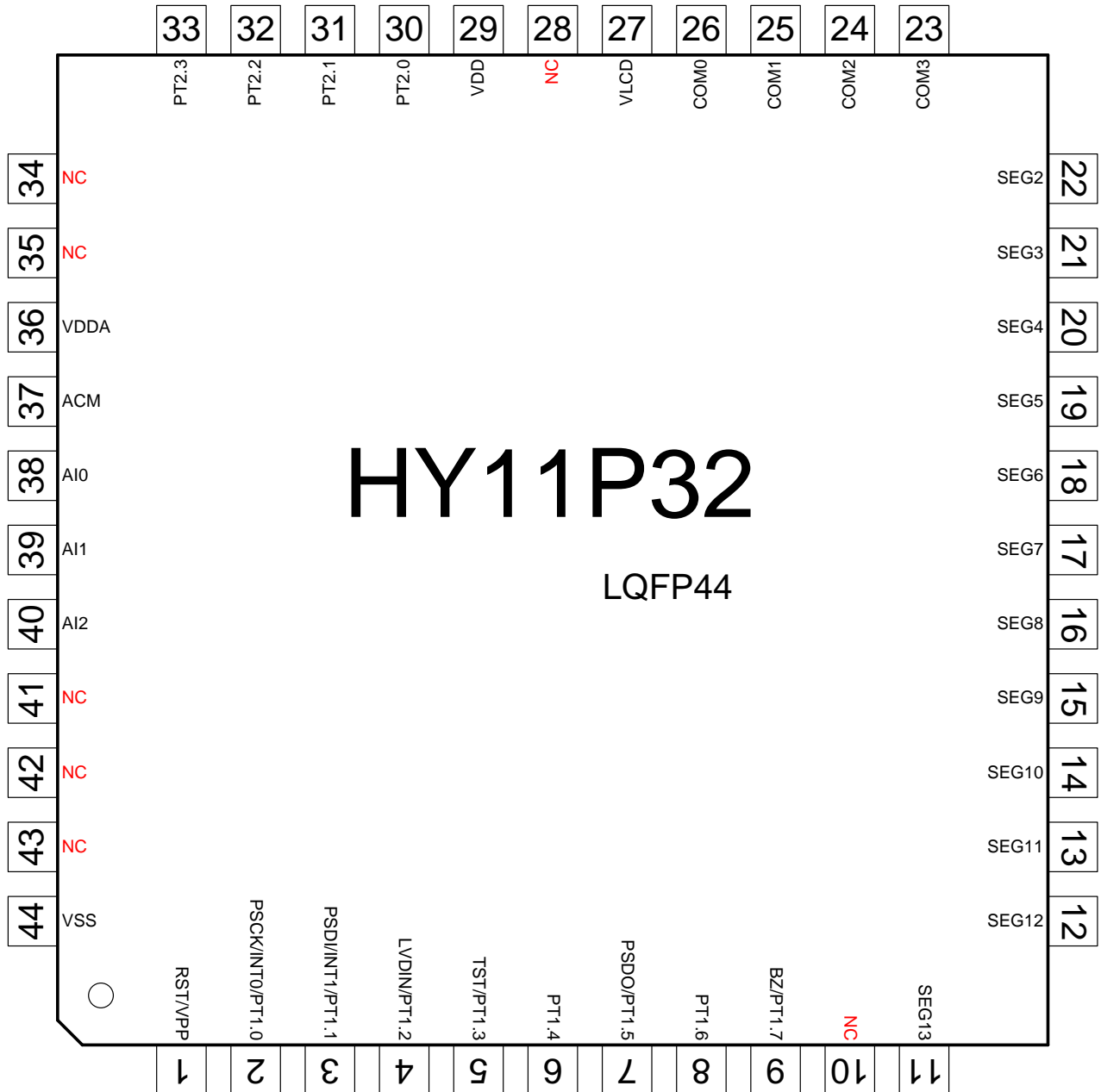


圖 2-1 HY11P32 LQFP44 引腳圖

註 1：VPP 與 RST 復用同一接口，非燒錄 EPROM 時禁止輸入電壓超過 5.8V

註 2：TST 與 PT1.3 復用同一接口，操作時禁止輸入電壓超過 Vdd+0.3V

註 3：若不將 PT1.3 設定成外部引腳按鍵，可以提升抗干擾能力

2.2 LQFP48 引腳圖

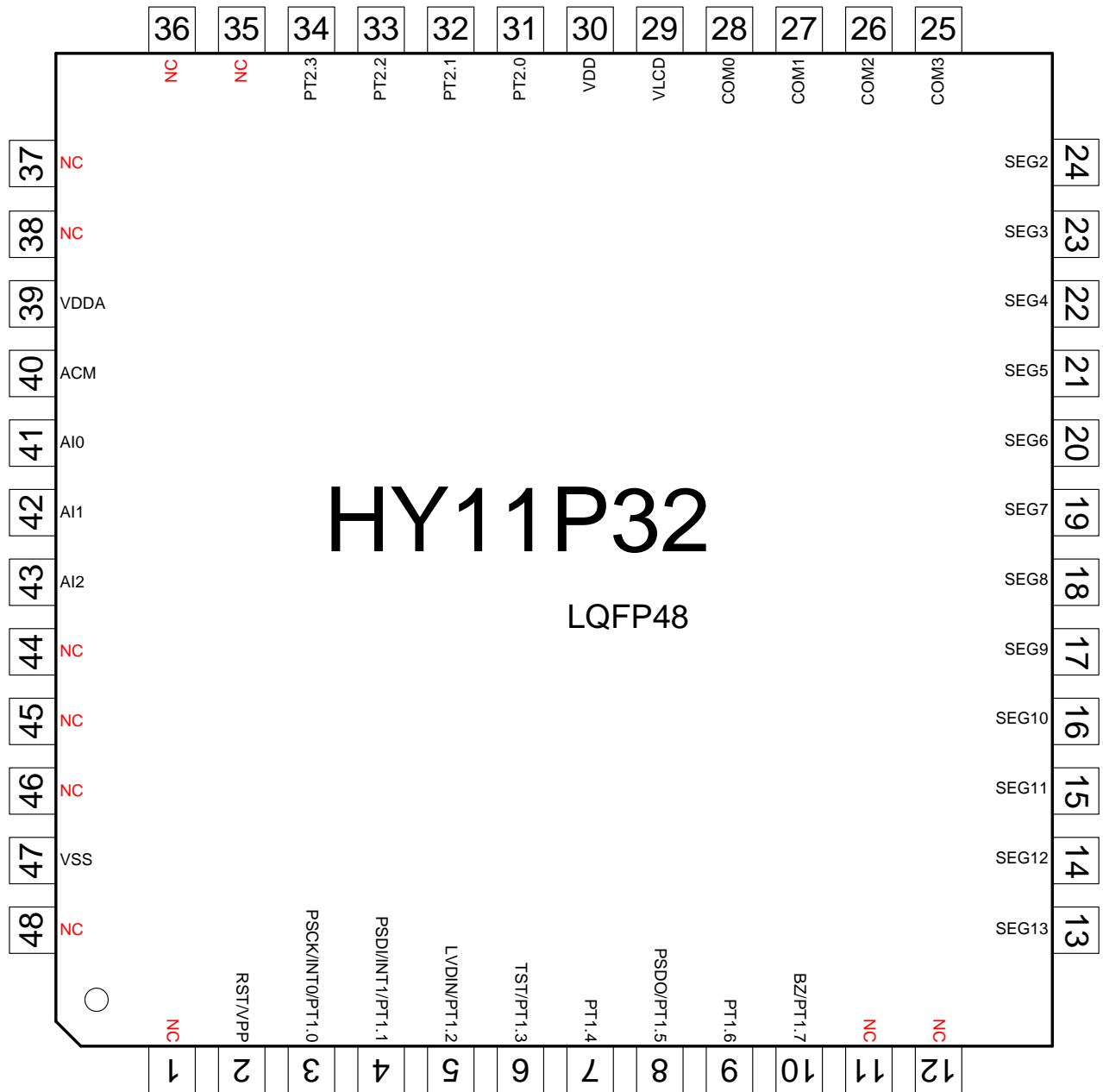


圖 2-1 HY11P32 LQFP48 引腳圖

註 1：VPP 與 RST 復用同一接口，非燒錄 EPROM 時禁止輸入電壓超過 5.8V

註 2：TST 與 PT1.3 復用同一接口，操作時禁止輸入電壓超過 Vdd+0.3V

註 3：若不將 PT1.3 設定成外部引腳按鍵，可以提升抗干擾能力

2.3 I/O 定義與說明(LQFP44)

“I/O”輸入/輸出,“I”輸入,“O”輸出,“S”史密斯觸發,“C”CMOS 特性兼容輸出與輸入,“P”電壓源,“A”類比通道

| 編號 | 引腳名稱 | 引腳特性 | | 功能說明 | |
|----|-----------------|-------|-----|------|------------------|
| | | 格式 | 緩衝 | | |
| 1 | RST/VPP | RST | I | S | 復位晶片 |
| | | VPP | P | P | EPROM 讀/寫時的電壓源 |
| 2 | PT1.0/INT0/PSCK | PT1.0 | I | S | 數位輸入 |
| | | INT0 | I | S | 中斷源 INT0 |
| | | PSCK | I | S | OTP 讀/寫介面 SCK 接口 |
| 3 | PT1.1/INT1/PSDI | PT1.1 | I | S | 數位輸入 |
| | | INT1 | I | S | 中斷源 INT1 |
| | | PSDI | I | S | OTP 讀/寫介面 SDI 接口 |
| 4 | PT1.2/LVDIN | PT1.2 | I | S | 數位輸入 |
| | | LVDIN | A | A | LVD 外部信號輸入接口 |
| 5 | PT1.3/TST | PT1.3 | I | S | 數位輸入 |
| | | TST | I | S | 測試模式致能輸入 (未開放) |
| 6 | PT1.4 | | I/O | S | 數位輸入/輸出 |
| 7 | PT1.5/PSDO | PT1.5 | I/O | S | 數位輸入/輸出 |
| | | PSDO | O | C | OTP 讀/寫介面 SDO 接口 |
| 8 | PT1.6 | | I/O | S | 數位輸入/輸出 |
| 9 | PT1.7/BZ | PT1.7 | I/O | S | 數位輸入/輸出 |
| | | BZ | O | C | 蜂鳴器輸出端 |
| 10 | NC | | - | - | 未使用 |
| 11 | SEG13 | | O | A | LCD 的 Segment 輸出 |
| 12 | SEG12 | | O | A | LCD 的 Segment 輸出 |
| 13 | SEG11 | | O | A | LCD 的 Segment 輸出 |
| 14 | SEG10 | | O | A | LCD 的 Segment 輸出 |
| 15 | SEG9 | | O | A | LCD 的 Segment 輸出 |
| 16 | SEG8 | | O | A | LCD 的 Segment 輸出 |

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| | | | | |
|----|-------|-----|---|------------------|
| 17 | SEG7 | O | A | LCD 的 Segment 輸出 |
| 18 | SEG6 | O | A | LCD 的 Segment 輸出 |
| 19 | SEG5 | O | A | LCD 的 Segment 輸出 |
| 20 | SEG4 | O | A | LCD 的 Segment 輸出 |
| 21 | SEG3 | O | A | LCD 的 Segment 輸出 |
| 22 | SEG2 | O | A | LCD 的 Segment 輸出 |
| 23 | COM3 | O | A | LCD 的 COM 輸出 |
| 24 | COM2 | O | A | LCD 的 COM 輸出 |
| 25 | COM1 | O | A | LCD 的 COM 輸出 |
| 26 | COM0 | O | A | LCD 的 COM 輸出 |
| 27 | VLCD | P | P | LCD 的電壓源 |
| 28 | NC | - | - | 未使用 |
| 29 | VDD | P | P | 晶片工作電壓源 |
| 30 | PT2.0 | I/O | S | 數位輸入/輸出 |
| 31 | PT2.1 | I/O | S | 數位輸入/輸出 |
| 32 | PT2.2 | I/O | C | 數位輸入/輸出 |
| 33 | PT2.3 | I/O | S | 數位輸入/輸出 |
| 34 | NC | - | - | 未使用 |
| 35 | NC | - | - | 未使用 |
| 36 | VDDA | P | P | 穩壓器輸出·類比電路電壓源 |
| 37 | ACM | P | P | 內部類比電路共地引腳 |
| 38 | AI0 | A | A | 類比輸入通道 |
| 39 | AI1 | A | A | 類比輸入通道 |
| 40 | AI2 | A | A | 類比輸入通道 |
| 41 | NC | - | - | 未使用 |
| 42 | NC | - | - | 未使用 |
| 43 | NC | - | - | 未使用 |
| 44 | VSS | P | P | 晶片工作電壓源接地端 |

表 2-1 引腳定義與功能說明

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3. 應用電路

3.1 橋式感測器 I

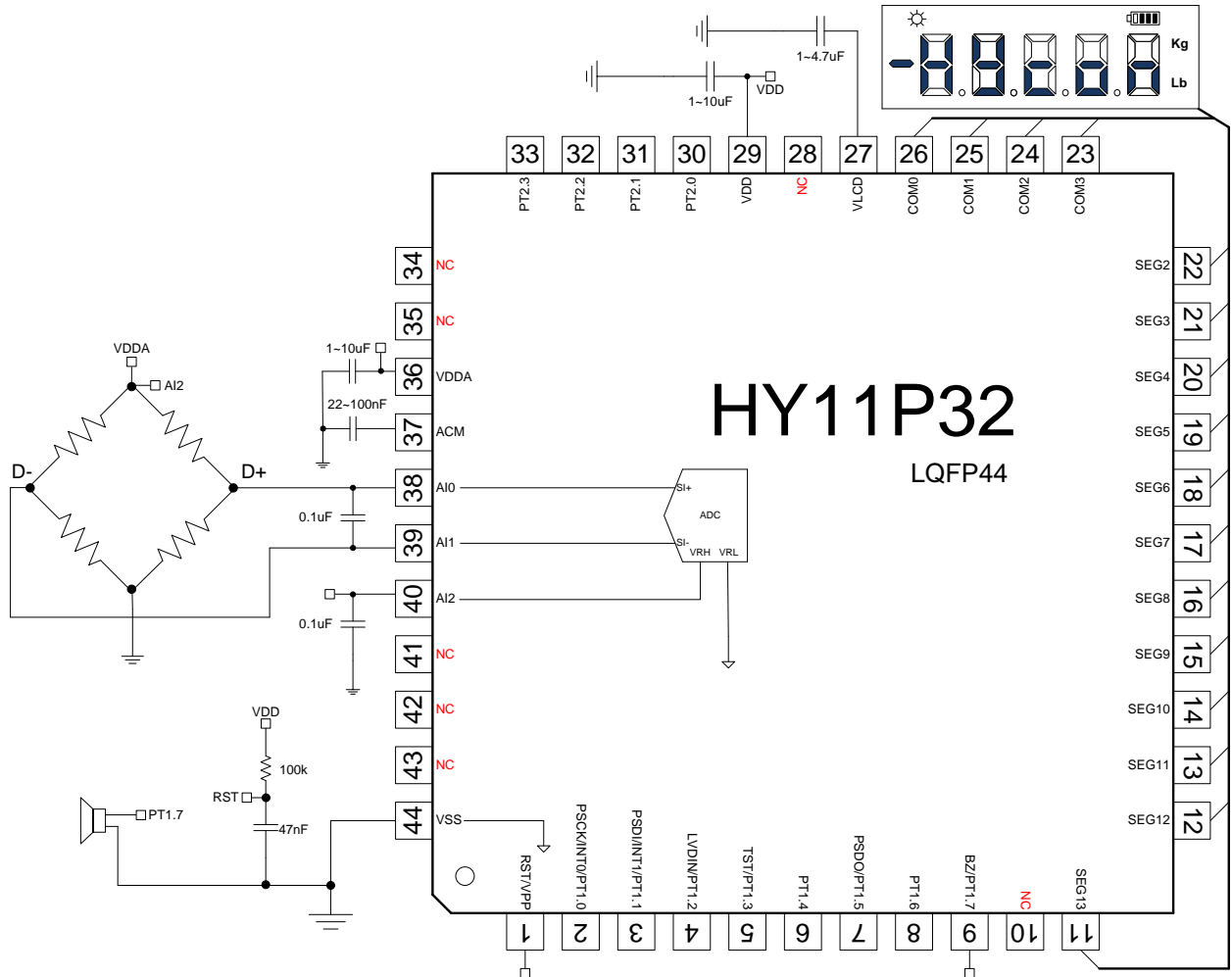


圖 3-1 橋式感測器應用電路

註：Load Cell 零點電壓位置可透過 DCSET[2:0] 進行偏壓調整。

4. 功能概述

4.1 内部方块图

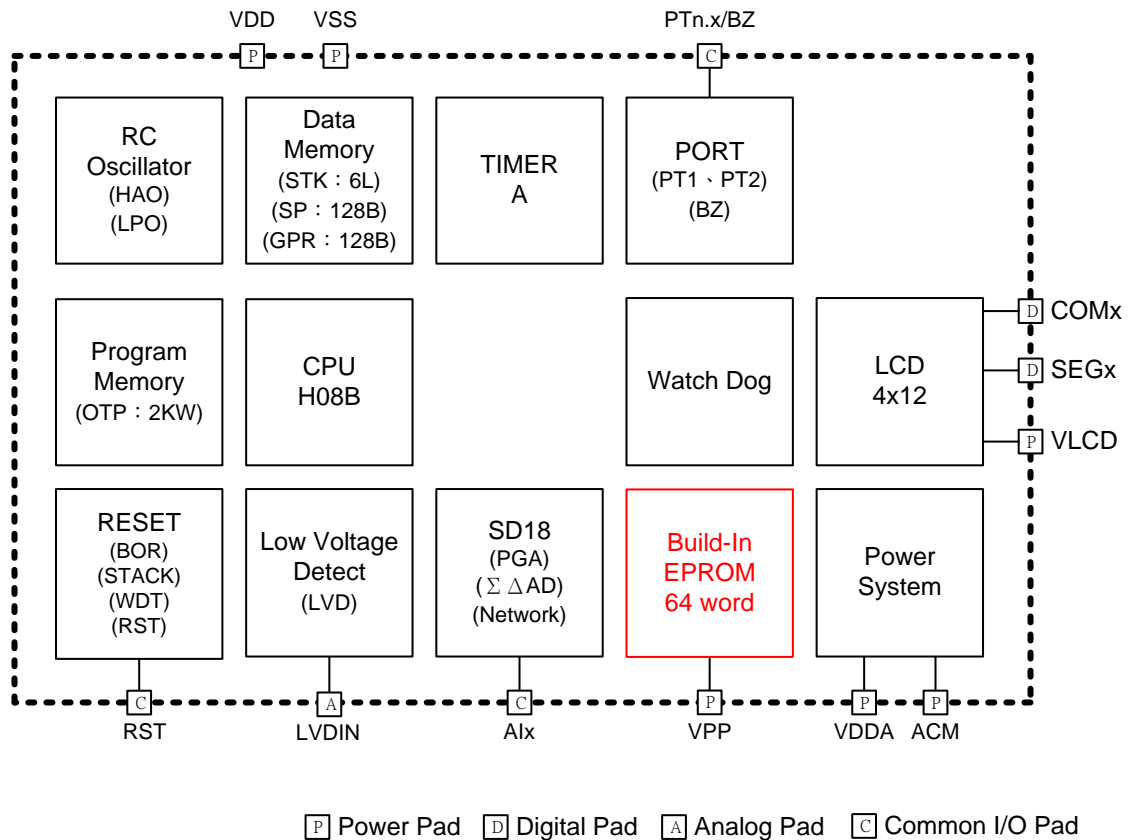


圖 4-1 HY11P32 内部方块图

4.2 相關說明與支援文件

晶片功能相關使用說明書

| | |
|-----------------|-----------------|
| DS-HY11P32-Vxx | HY11P32 說明書 |
| UG-HY11S14-Vxx | HY11Pxx 系列使用說明書 |
| APD-CORE003-Vxx | H08B 指令說明書 |

開發工具相關使用說明書

| | |
|------------------|-----------------------|
| APD-HYIDE006-Vxx | HY11xxx 系列開發工具軟體使用說明書 |
| APD-HYIDE005-Vxx | HY11xxx 系列開發工具硬體使用說明書 |
| APD-OTP001-Vxx | OTP 產品燒錄引腳說明書 |

產品生產相關使用說明書

| | |
|------------------|-----------------------|
| APD-HYIDE004-Vxx | HY1xxxx 系列生產線專用燒錄器說明書 |
| BDI-HY11P32-Vxx | HY11P32 個別產品的裸片打線資訊 |

4.3 SD18 Network

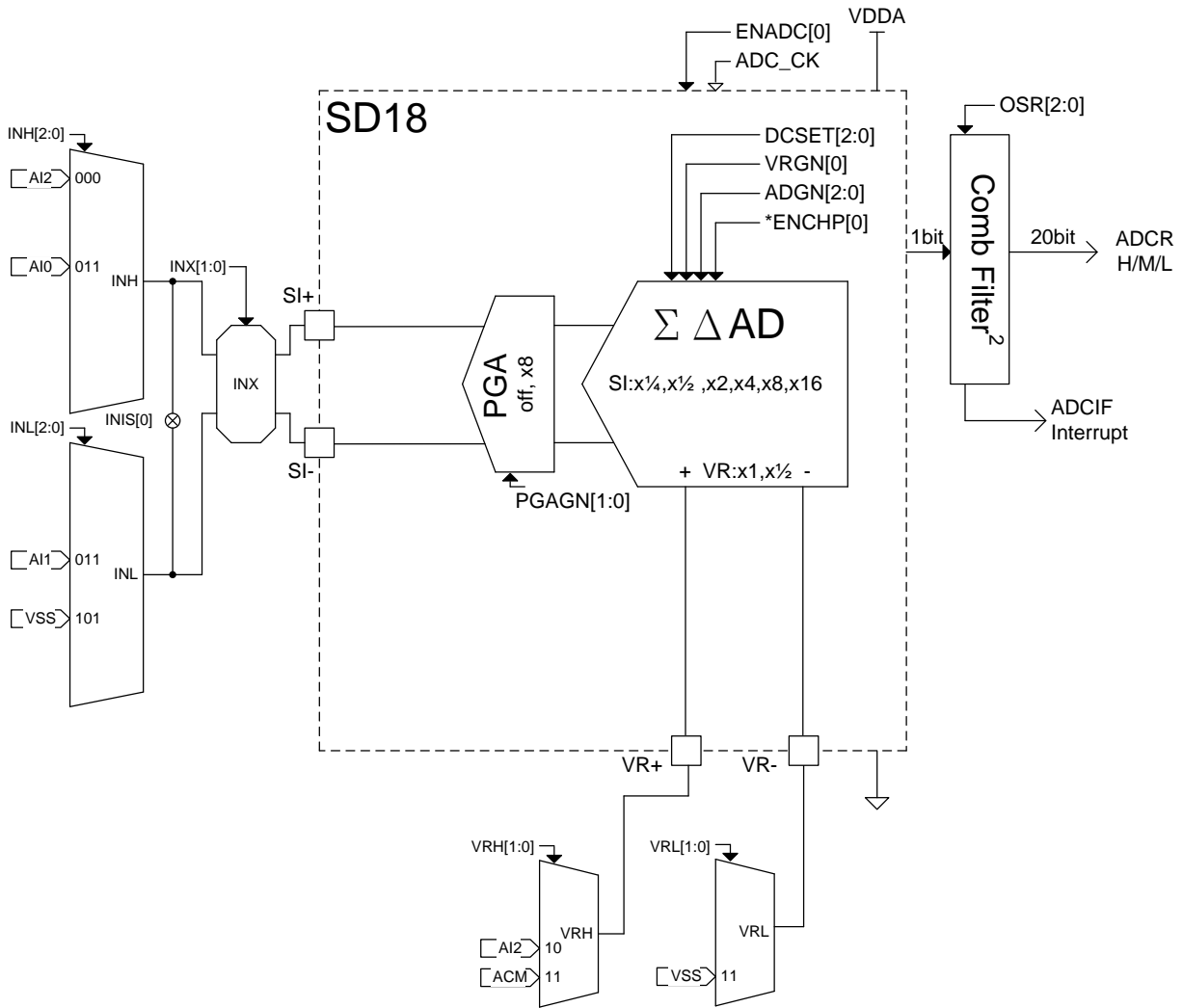


圖 4-2 SD18 Network

5. 暫存器列表

| Register File Summary for H08B | | | | | | | | | | | | | | |
|---|------------------------------------|--|---------------|---------------|---------------------------------|------------|------------------|------------|-------------|-----------|-----------|------------------------|---------------------------|------------|
| “-”no use, “r”read/write, “w”write, “r”read, “r0”only read 0, “r1”only read 1, “w0”only write 0, “w1”only write 1 | | | | | | | | | | | | | | |
| “.”unimplemented bit, “x”unknown, “u”unchanged, “d”depends on condition | | | | | | | | | | | | | | |
| Address | File Name | Bit7 | Bit6 | Bit5 | Bit4 | Bit3 | Bit2 | Bit1 | Bit0 | A-RESET | I-RESET | R/W | | |
| 00H | INDF0 | Contents of FSR0 to address data memory -value of FSR0 not changed | | | | | | | | | | N/A | N/A | r, r0, r1 |
| 10H | FSR0L | Indirect Data Memory Address Pointer 0 Low Byte, FSR0[7:0] | | | | | | | | | | xxxx xxxx | uuuu uuuu | r, r0, r1 |
| 18H | STKPTR | STKFL | STKUN | STKOV | | | | STKPR[2:0] | | | 000..000 | 000..000 | r, r0, r1 | |
| 1AH | PCLATH | | | | | | | PC[10] | PC[9] | PC[8] |000 |000 | r, r0, r1 | |
| 1BH | PCLATL | PC Low Byte for PC<7:0> | | | | | | | | | | 0000 0000 | 0000 0000 | r, r0, r1 |
| 1CH | BICTRL | | | | VPP_HIGH | | BIEWR | | BIERD | | 1000 d000 | 1000 d000 | r, r0, r1 | |
| 1EH | BIEPTRL | 0 | 0 | BIE_ADDR[5:0] | | | | | | | 0000 0000 | 0000 0000 | w0, w0, r1 | |
| 1FH | BIEDH | BIE_DATA[15:8] | | | | | | | | | | xxxx xxxx | xxxx xxxx | r, r0, r1 |
| 20H | BIEDL | BIE_DATA[7:0] | | | | | | | | | | xxxx xxxx | xxxx xxxx | r, r0, r1 |
| 23H | INTE1 | GIE | ADCIE | | | TMAIE | WDTIE | E1IE | E0IE | 0000 0000 | 0000 0000 | r, r0, r1 | | |
| 26H | INTF1 | ADCIF | | | | TMAIF | WDTIF | E1IF | E0IF | .000 0000 | .000 0000 | r, r0, r1 | | |
| 29H | WREG | Working Register | | | | | | | | | | xxxx xxxx | uuuu uuuu | r, r0, r1 |
| 2BH | STATUS | | | | C | | | Z | | | xxxx xxxx | xxxx xxxx | r, r0, r1 | |
| 2CH | Pstatus | PD | TO | IDLEB | BOR | SKERR | | | | | 000d xxxx | 000d xxxx | rw0, rw0, rw0, x, x, x, x | |
| 2DH | LVDCN | LVDFG | | LVD | LVDON | VLDX[3:0] | | | | | x000 0000 | x000 0000 | x, x, x, x | |
| 30H | PWRCN | ENVDDA | VDDAX[1:0]=11 | | ENACM | | | | | | 0xx0 xxxx | 0xx0 xxxx | r, r0, r1 | |
| 31H | MCKCN1 | ADCS[2:0] | | ADCK | | | ENXT=0 | ENHAO | | 0000 0001 | 0000 0001 | r, r0, r1 | | |
| 32H | MCKCN2 | LSCK=0 | | HSCK=0 | HSS[1:0]=00 | | CPUCK[1:0] | | | | .00 0000 | .00 0000 | r0, r0, r0, r0 | |
| 33H | MCKCN3 | LCDS[2:0] | | | PERCK | | BZS[2:0] | | | | 000. 0000 | 000. 0000 | r, r0, r1 | |
| 39H | ADCRH | ADC conversion memory HighByte | | | | | | | | | | xxxx xxxx | uuuu uuuu | r, r0, r1 |
| 3AH | ADCRM | ADC conversion memory Middle Byte | | | | | | | | | | xxxx xxxx | uuuu uuuu | r, r0, r1 |
| 3BH | ADCRL | ADC conversion memory Low Byte | | | | | | | | | | xxxx xxxx | uuuu uuuu | r, r0, r1 |
| 3CH | ADCCN1 | ENADC | ENCHP | | PGAGN[1:0]=00 or 11 | ADGN[2:0] | | | | | 0000 0000 | 0000 0000 | r, r0, r1 | |
| 3DH | ADCCN2 | INBUF=0 | | VRBUF=0 | VREGN | DCSET[2:0] | | | | | 0000 0000 | 0000 0000 | r0, r0, r0 | |
| 3EH | ADCCN3 | OSR[2:0] | | | | | | | | | | 0000 0000 | 0000 0000 | r, r0, r1 |
| 3FH | AINET1 | INH[2:0]=XX0 or XX1(AI2 or AI0) | | | INL[2:0]=0XX or 1XX(AI1 or VSS) | | INIS | | | | | xx00 xx0x | xx00 xx0x | x, x, x, x |
| 40H | AINET2 | VRH[1:0]=X0 or X1(AI2 or ACM) | | | INX[1:0] | | VRL[1:0]=11(VSS) | | | | | xx00 0xxx | xx00 0xxx | x, x, x, x |
| 41H | TMACN | ENTMA | TMACK | TMAS[1:0] | | ENWDT | WDT[2:0] | | | | | 0000 0000 | 0000 0000 | r, r0, r1 |
| 42H | TMAR | TimerA data register | | | | | | | | | | xxxx xxxx | uuuu uuuu | r, r0, r1 |
| 52H | LCDCN1 | ENLCD | LCDPR | VLCDX[1:0] | | LCDBF | LCDB[1:0]=10 | | | | | 0000 0xxx | 0000 0xxx | x, x, x, x |
| 53H | LCDCN2 | LCDBL | LCDMX[1:0]=11 | | | | | | | | 0xxx xxxx | 0xxx xxxx | x, x, x, x | |
| 54H | LCD0 | Segment SEG2@[3:0] and SEG3@[7:4] data register of LCD0 | | | | | | | | | | xxxx xxxx | uuuu uuuu | r, r0, r1 |
| 55H | LCD1 | Segment SEG4@[3:0] and SEG5@[7:4] data register of LCD1 | | | | | | | | | | xxxx xxxx | uuuu uuuu | r, r0, r1 |
| 56H | LCD2 | Segment SEG6@[3:0] and SEG7@[7:4] data register of LCD2 | | | | | | | | | | xxxx xxxx | uuuu uuuu | r, r0, r1 |
| 57H | LCD3 | Segment SEG8@[3:0] and SEG9@[7:4] data register of LCD3 | | | | | | | | | | xxxx xxxx | uuuu uuuu | r, r0, r1 |
| 58H | LCD4 | Segment SEG10@[3:0] and SEG11@[7:4] data register of LCD4 | | | | | | | | | | xxxx xxxx | uuuu uuuu | r, r0, r1 |
| 59H | LCD5 | Segment SEG12@[3:0] and SEG13@[7:4] data register of LCD5 | | | | | | | | | | xxxx xxxx | uuuu uuuu | r, r0, r1 |
| 6DH | PT1 | PT1.7 | PT1.6 | PT1.5 | PT1.4 | PT1.3 | PT1.2 | PT1.1 | PT1.0 | xxxx xxxx | uuuu uuuu | r, r0, r1 | | |
| 6EH | TRISC1 | TC1.7 | TC1.6 | TC1.5 | TC1.4 | | | | | | 0000 0000 | 0000 0000 | r0, r0, r0 | |
| 70H | PT1PU | PU1.7 | PU1.6 | PU1.5 | PU1.4 | PU1.3 | PU1.2 | PU1.1 | PU1.0 | 0000 0000 | 0000 0000 | r, r0, r1 | | |
| 71H | PT1M1 | | | | | | INTEG1[1:0] | | INTEG0[1:0] | | 0000 0000 | 0000 0000 | r0, r0, r0 | |
| 72H | PT1M2 | PM1.7[0] | | | | | | | | 0000 0000 | 0000 0000 | r0, r0, r0, r0, r0, r0 | | |
| 74H | PT2 | | | | | PT2.3 | PT2.2 | PT2.1 | PT2.0 | xxxx | uuuu | x, x, x, x | | |
| 75H | TRISC2 | | | | | TC2.3 | TC2.2 | TC2.1 | TC2.0 | 0000 | 0000 | x, x, x, x | | |
| 77H | PT2PU | | | | | PU2.3 | PU2.2 | PU2.1 | PU2.0 | 0000 | 0000 | x, x, x, x | | |
| 80H - FFH | GENERAL PURPOSE REGISTER @ 128Byte | | | | | | | | | | xxxx xxxx | uuuu uuuu | r, r0, r1 | |

圖 5-1 HY11P32 暫存器列表

6. 電氣特性

Absolute maximum ratings over operating free-air temperature (unless otherwise noted)

| | |
|---|----------------------------|
| Voltage applied at V_{DD} to V_{SS} | -0.2 V to 4.0 V |
| Voltage applied to any pin | -0.2 V to $V_{DD} + 0.3$ V |
| Voltage applied to RST/VPP pin | -0.2 V to 6.9 V |
| Voltage applied to TST/PT1.3 pin | -0.2 V to $V_{DD} + 1$ V |
| Diode current at any device terminal | ± 2 mA |
| Storage temperature, Tstg: (unprogrammed device) | -55°C to 150°C |
| (programmed device) | -40°C to 85°C |
| Total power dissipation | 0.5w |
| Maximum output current sink by any PORT1 to PORT2 I/O pin | 25mA |

6.1 Recommended operating conditions

$T_A = -40^\circ\text{C} \sim 85^\circ\text{C}$, unless otherwise noted

| Sym. | Parameter | Test Conditions | Min. | Typ. | Max. | unit |
|----------|----------------|---------------------------------|------|------|------|------|
| V_{DD} | Supply Voltage | All digital peripherals and CPU | 2.2 | | 3.6 | V |
| | | Analog peripherals | 2.4 | | 3.6 | |
| V_{SS} | Supply Voltage | | 0 | | 0 | |

6.2 Internal RC Oscillator

$T_A = 25^\circ\text{C}, V_{DD} = 3.0\text{V}$, unless otherwise noted

| Sym. | Parameter | Test Conditions | Min. | Typ. | Max. | unit |
|------|---------------------------------|---------------------------------------|------|------|------|------|
| HAO | High Speed Oscillator frequency | ENHAO[0]=1 | 1.6 | 2.0 | 2.4 | MHz |
| LPO | Low Power Oscillator frequency | V_{DD} supply voltage be enable LPO | 22 | 28 | 35 | KHz |

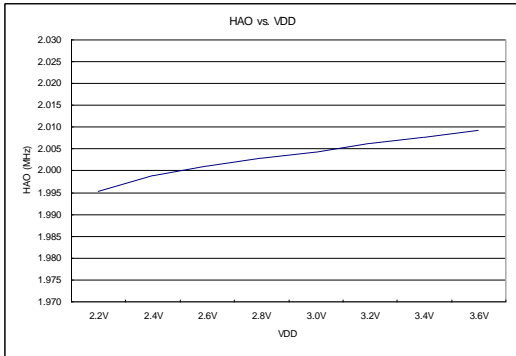


Figure 6.2-1 HAO vs. VDD

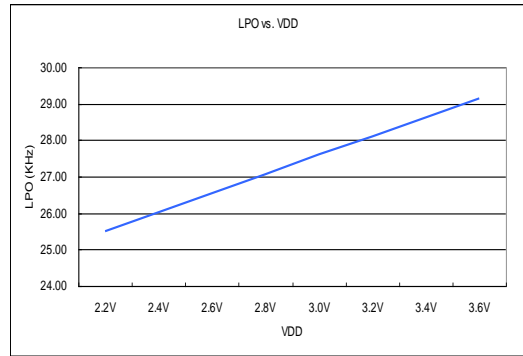


Figure 6.2-2 LPO vs. VDD

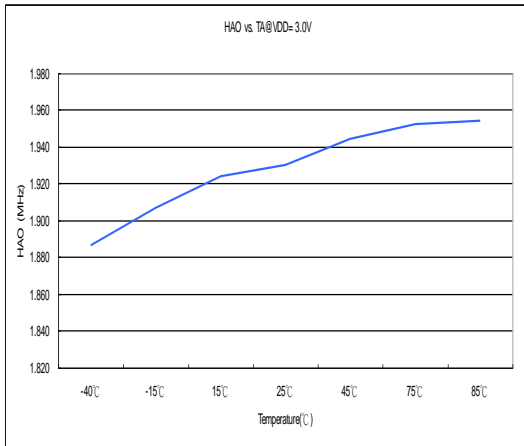


Figure 6.2-3 HAO vs. Temperature

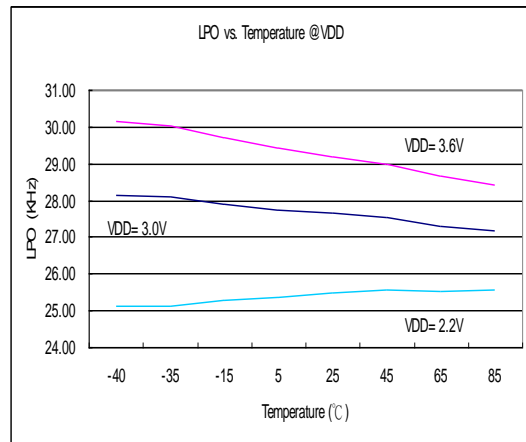


Figure 6.2-4 LPO vs. Temperature

6.3 Supply current into VDD excluding peripherals current

$T_A = 25^\circ\text{C}, V_{DD} = 3.0\text{V}, \text{OSC_LPO} = 28\text{KHz}$, unless otherwise noted

| Sym. | Parameter | Test Conditions | Min. | Typ. | Max. | unit |
|------------------|---------------|--|------|-------|------|------|
| I _{AM2} | Active mode 2 | OSC_CY = off, OSC_HAO = 2MHz, CPU_CK = 2MHz | | 0.28 | 0.55 | mA |
| I _{AM3} | Active mode 3 | OSC_CY = off, OSC_HAO = 2MHz, CPU_CK = 1MHz | | 0.165 | 0.3 | mA |
| I _{LP2} | Low Power 2 | OSC_CY = off, OSC_HAO = off, CPU_CK = LPO, Idle state | | 1.65 | 3 | uA |
| I _{LP3} | Low Power 3 | OSC_CY = off, OSC_HAO = off, CPU_CK = off, Sleep state | | 0.65 | 1.2 | uA |

OSC_HAO : Internal High Accuracy Oscillator frequency.

CPU_CK : CPU core work frequency.

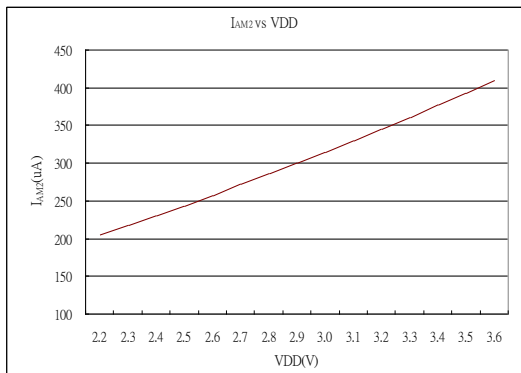


Figure 6.3-1 I_{AM2} vs. VDD

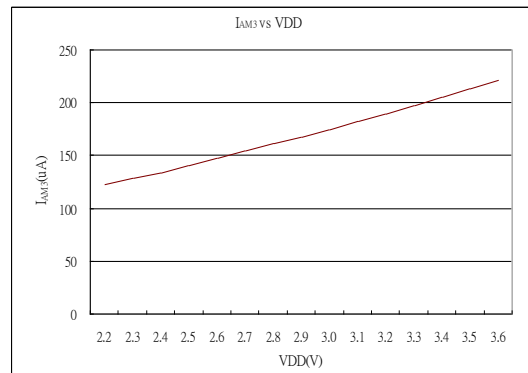


Figure 6.3-2 I_{AM3} vs. VDD

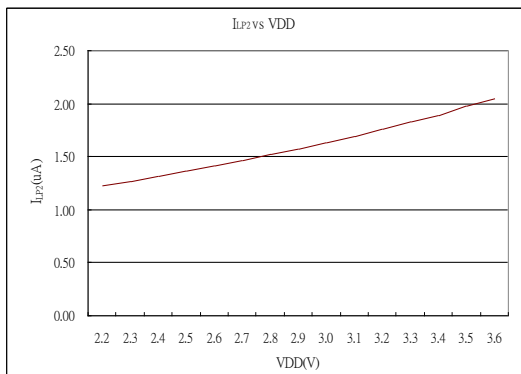


Figure 6.3-3 I_{LP2} vs. VDD

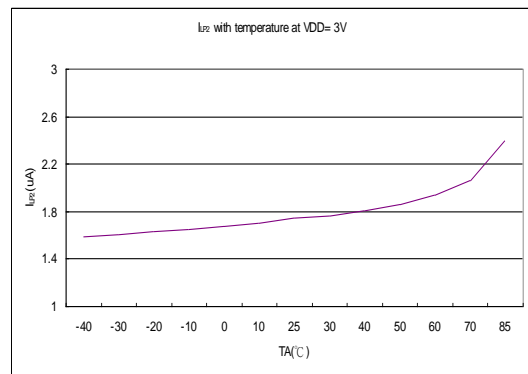


Figure 6.3-4 I_{LP2} vs. Temperature

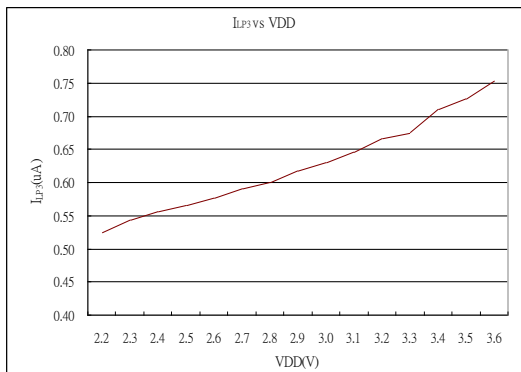


Figure 6.3-5 I_{LP3} vs. VDD

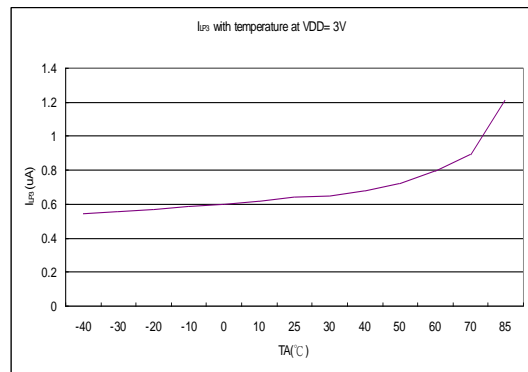


Figure 6.3-6 I_{LP3} vs. Temperature

6.4 Port1~2

$T_A = 25^\circ\text{C}, V_{DD} = 3.0\text{V}$, unless otherwise noted

| Sym. | Parameter | Test Conditions | Min. | Typ. | Max. | unit |
|---|---|-----------------------|----------------|------|----------------|------------------|
| Input voltage and Schmitt trigger and leakage current and timing | | | | | | |
| V_{IH} | High-Level input voltage | | | | 2.1 | V |
| V_{IL} | Low-Level input voltage | | 0.9 | | | |
| V_{hys} | Input Voltage hysteresis($V_{IH} - V_{IL}$) | | | 0.8 | | V |
| I_{LKG} | Leakage Current | | | | 0.1 | μA |
| R_{PU} | Port pull high resistance | | | 180 | | $\text{k}\Omega$ |
| Output voltage and current and frequency | | | | | | |
| V_{OH} | High-level output voltage | $I_{OH}=10\text{mA}$ | $V_{DD} - 0.3$ | | | V |
| V_{OL} | Low-level output voltage | $I_{OL}=-10\text{mA}$ | | | $V_{SS} + 0.3$ | |

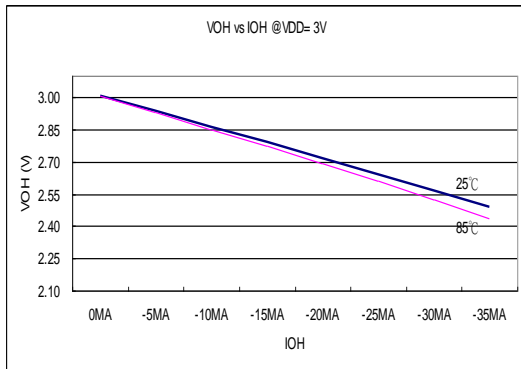


Figure 6.4-1 V_{OH} vs. I_{OH} @ $V_{DD}=3.0\text{V}$

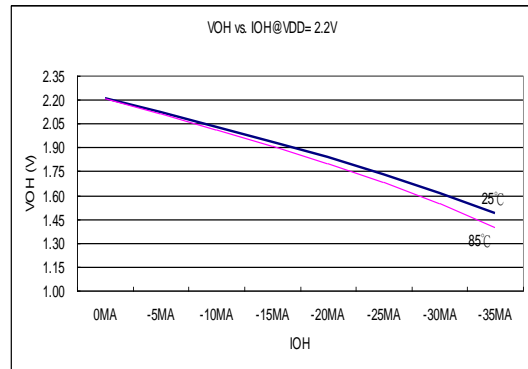


Figure 6.4-2 V_{OH} vs. I_{OH} @ $V_{DD}=2.2\text{V}$

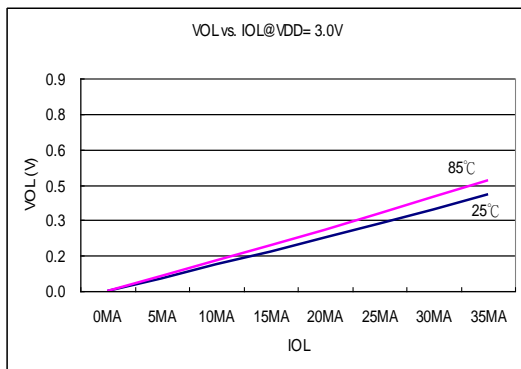


Figure 6.4-3 V_{OL} vs. I_{OL} @ $V_{DD}=3.0\text{V}$

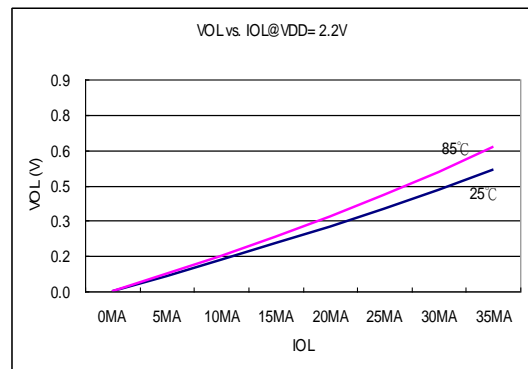


Figure 6.4-4 V_{OL} vs. I_{OL} @ $V_{DD}=2.2\text{V}$

6.5 Reset(Brownout, External RST pin, Low Voltage Detect)

$T_A = 25^\circ\text{C}, V_{DD} = 3.0\text{V}$, unless otherwise noted

| Sym. | Parameter | Test Conditions | Min. | Typ. | Max. | unit | |
|------|--|---|------|------|------|--------|--|
| BOR | Pulse length needed to accepted reset internally, t_{d-LVR} | | 2 | | | us | |
| | V_{DD} Start Voltage to accepted reset internally (L→H), V_{LVR} | | 1.6 | 1.85 | 2.1 | V | |
| | Hysteresis, $V_{HYS-LVR}$ | | | 70 | | mV | |
| RST | Pulse length needed as RST/VPP pin to accepted reset internally, t_{d-RST} | | 2 | | | us | |
| | Input Voltage to accepted reset internally | | 0.9 | | | V | |
| | Hysteresis, $V_{HYS-RST}$ | | | 0.8 | | V | |
| LVD | Operation current, I_{LVD} | | | 10 | 15 | uA | |
| | External input voltage to compare reference voltage | | | 1.2 | | V | |
| | Compare reference voltage temperature drift | $T_A = -40^\circ\text{C} \sim 85^\circ\text{C}$ | | 100 | | ppm/°C | |
| | Detect V_{DD} voltage rang by user option, $V_{SVS} VLDx[3:0]=1110b$ | | | 3.3 | | V | |
| | Detect V_{DD} voltage rang by user option, $V_{SVS} VLDx[3:0]=1101b$ | | | 3.2 | | | |
| | Detect V_{DD} voltage rang by user option, $V_{SVS} VLDx[3:0]=1100b$ | | | 3.1 | | | |
| | Detect V_{DD} voltage rang by user option, $V_{SVS} VLDx[3:0]=1011b$ | | | 3.0 | | | |
| | Detect V_{DD} voltage rang by user option, $V_{SVS} VLDx[3:0]=1010b$ | | | 2.9 | | | |
| | Detect V_{DD} voltage rang by user option, $V_{SVS} VLDx[3:0]=1001b$ | | | 2.8 | | | |
| | Detect V_{DD} voltage rang by user option, $V_{SVS} VLDx[3:0]=1000b$ | | | 2.7 | | | |
| | Detect V_{DD} voltage rang by user option, $V_{SVS} VLDx[3:0]=0111b$ | | | 2.6 | | | |
| | Detect V_{DD} voltage rang by user option, $V_{SVS} VLDx[3:0]=0110b$ | | | 2.5 | | | |
| | Detect V_{DD} voltage rang by user option, $V_{SVS} VLDx[3:0]=0101b$ | | | 2.4 | | | |
| | Detect V_{DD} voltage rang by user option, $V_{SVS} VLDx[3:0]=0100b$ | | | 2.3 | | | |
| | Detect V_{DD} voltage rang by user option, $V_{SVS} VLDx[3:0]=0011b$ | | | 2.2 | | | |
| | Detect V_{DD} voltage rang by user option, $V_{SVS} VLDx[3:0]=0010b$ | | | 2.1 | | | |
| | Detect V_{DD} voltage rang by user option, $V_{SVS} VLDx[3:0]=0001b$ | | | 2.0 | | | |
| | BOR : Brownout Reset LVR : Low Voltage Reset of BOR LVD : Low Voltage Detect RST : External Reset pin | | | | | | |

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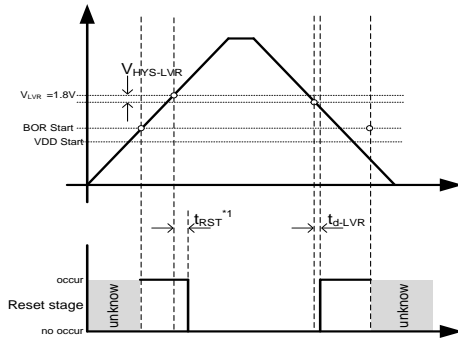


Figure 6.5-1 BOR reset diagram

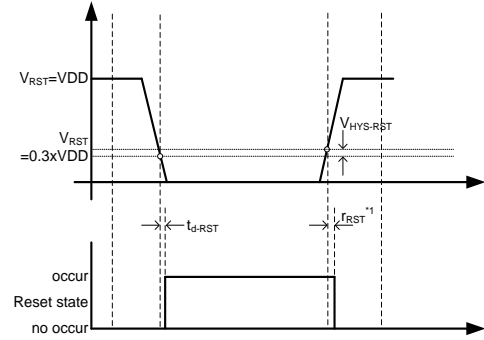


Figure 6.5-2 RST reset diagram

*1 t_{RST} : Please see BOR Introduce of HY11Pxx series User's Guide (UG-HY11S14-Vxx).

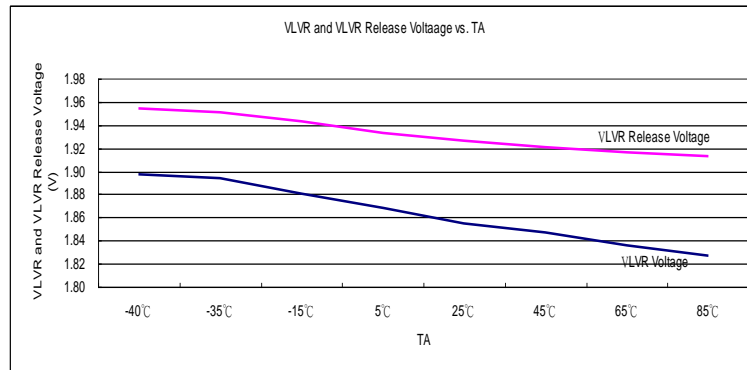


Figure 6.5-3 LVR vs. Temperature

6.6 Power System

$T_A = 25^\circ\text{C}, V_{DD} = 3.0\text{V}$, unless otherwise noted

| Sym. | Parameter | Test Conditions | | Min. | Typ. | Max. | unit |
|------|------------------------------------|--|---|-----------|------|------|------------------------|
| VDDA | VDDA operation current, I_{VDDA} | $I_L = 0\text{mA}$ | VDDAX[1:0]=00b | 22 | | | μA |
| | Select VDDA output voltage | $I_L = 0.1\text{mA}$, $V_{DD} \geq V_{VDDA} + 0.2\text{V}$ | VDDAX [1:0]=11b | 2.4 | | | V |
| | Dropout voltage | $I_L = 10\text{mA}$ | VDDAX [1:0]=11b | 180 | | | mV |
| | Temperature drift | VDDAX [1:0]=11b | $T_A = -40^\circ\text{C} \sim 85^\circ\text{C}$ | 50 | | | ppm/ $^\circ\text{C}$ |
| | V_{DD} Voltage drift | $I_L = 0.1\text{mA}$ | $V_{DD} = 2.5\text{V} \sim 3.6\text{V}$ | ± 0.2 | | | %/V |
| ACM | ACM operation current, I_{ACM} | $I_L = 0\text{mA}$ | | 20 | | | μA |
| | Output voltage, V_{ACM} | ENACM[0]=1 | $I_L = 0\mu\text{A}$ | 1.0 | | | V |
| | Output voltage with Load | | $I_L = \pm 200\mu\text{A}$ | 0.98 | 1.02 | | V_{ACM} |
| | Temperature drift | ENACM[0]=1, | $T_A = -40^\circ\text{C} \sim 85^\circ\text{C}$ | 50 | | | ppm/ $^\circ\text{C}$ |
| | VDDA Voltage drift | $I_L = 10\mu\text{A}$ | | 100 | | | $\mu\text{V}/\text{V}$ |

VDDA : Adjust Voltage Regulator
ACM : Analog Common Mode Voltage

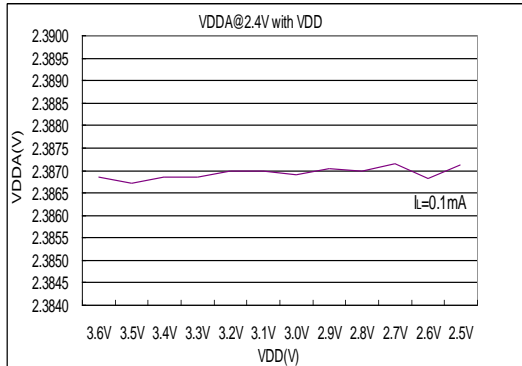


Figure 6.6-1 VDDA $I_L=0.1\text{mA}$ vs. VDD

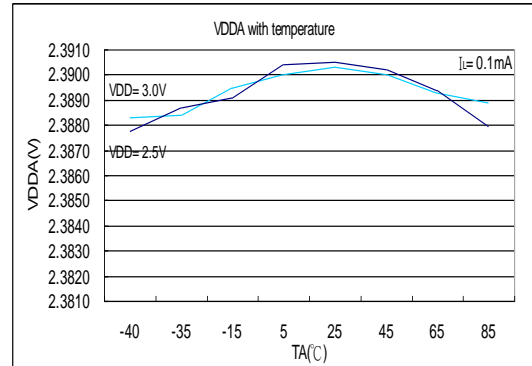


Figure 6.6-2 VDDA $I_L=0.1\text{mA}$ vs. Temperature

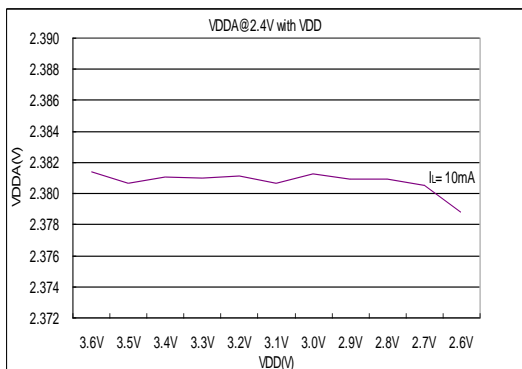


Figure 6.6-3 VDDA $I_L=10\text{mA}$ vs. VDD

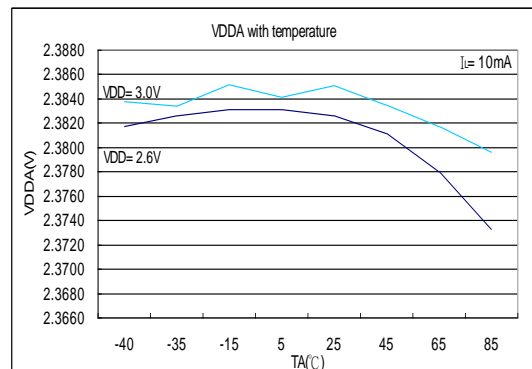


Figure 6.6-4 VDDA $I_L=10\text{mA}$ vs. Temperature

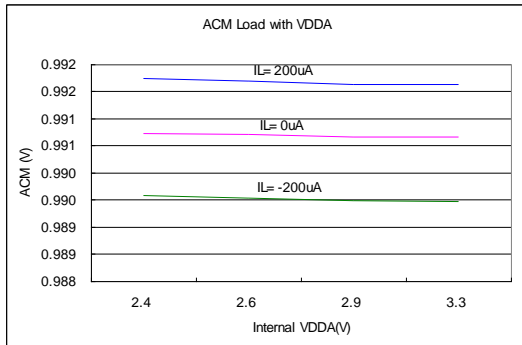


Figure6.6-5 ACM Load vs. VDDA

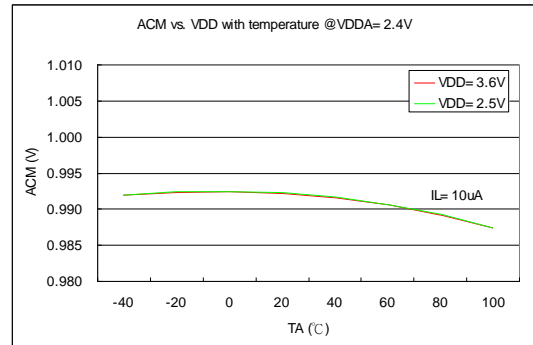


Figure6.6-6 ACM vs. Temperature

6.7 LCD

$T_A = 25^\circ\text{C}, V_{DD} = 3.0\text{V}, C_{VLCD} = 4.7\mu\text{F}$, unless otherwise noted.

| Sym. | Parameter | Test Conditions | Min. | Typ. | Max. | unit | |
|----------------|--|--|------------------------|-------|------|------------|----|
| I_{LCD} | Operation supply current without output buffer.(all segment turn on) | LCDPR[0]=1 | $V_{DD} = 2.2\text{V}$ | 20 | | | uA |
| | | | $V_{DD} = 3.0\text{V}$ | | | | |
| VLCD | Supply Voltage at VLCD pin | LCDPR[0]=0 | 2.2 | | 3.6 | V | |
| | Embedded Charge Pump output voltage at VLCD pin | $V_{DD} = 2.2\text{V}$, LCDPR[0]=1, $C_{VLCD} = 4.7\mu\text{F}$ | VLCDX[1:0]=11b | 2.295 | 2.55 | 2.805 | V |
| | | | VLCDX[1:0]=10b | 2.52 | 2.8 | 3.08 | |
| | | | VLCDX[1:0]=01b | 2.745 | 3.05 | 3.355 | |
| VLCDX[1:0]=00b | 2.97 | 3.3 | 3.63 | | | | |
| Z_{LCD} | Output impedance with LCD buffer | $f_{LCD} = 128\text{Hz}, VLCD = 3.05\text{V}$ | | 10 | | k Ω | |

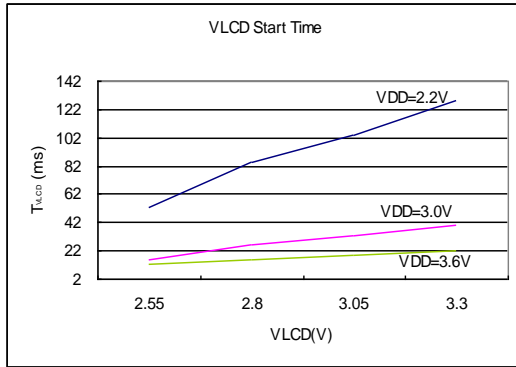


Figure6.7-1 LCD start time

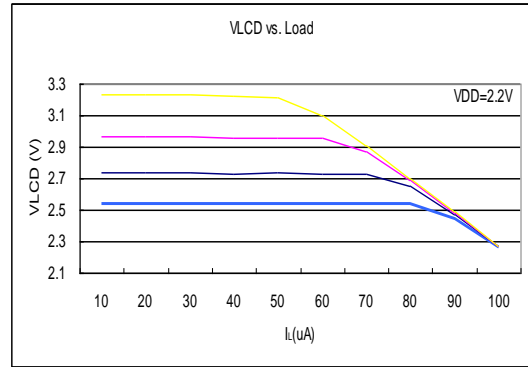


Figure6.7-2 VLCD vs. I_L @ VDD=2.2V

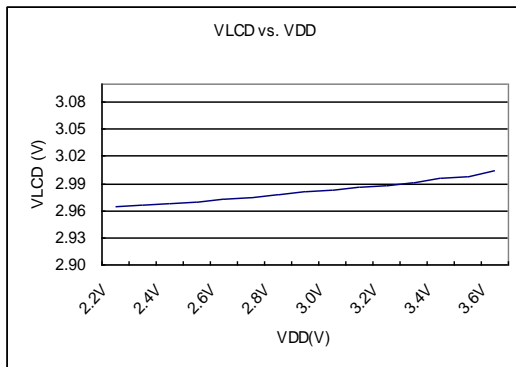


Figure6.7-3 VLCD vs. VDD

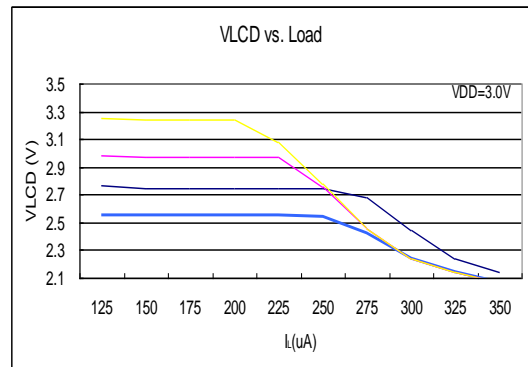


Figure6.7-4 VLCD vs. I_L @ VDD=3.0V

6.8 SD18, Power Supply and recommended operating conditions

$T_A = 25^\circ\text{C}, V_{DD} = 3.0\text{V}, V_{DDA} = 2.4\text{V}$, unless otherwise noted

| Sym. | Parameter | Test Conditions | | Min. | Typ. | Max. | unit |
|------------|--------------------------------------|--------------------------------------|---------------------------|------|------|-------|---------------|
| V_{SD18} | Supply Voltage at VDDA | ENVDDA[0]=0 | | 2.4 | | 3.6 | V |
| f_{SD18} | Modulator sample frequency, ADC_CK | | | 25 | 250 | 300 | KHz |
| | Over Sample Ratio, OSR | | | 256 | | 32768 | |
| I_{SD18} | Operation supply current without PGA | ENADC[0]=1 INBUF[0]=0, VRBUF[0]=0 | GAIN =4, ADC_CK=250KHz | | 120 | | μA |

6.8.1 PGA, Power Supply and recommended operating conditions

$T_A = 25^\circ\text{C}, V_{DD} = 3.0\text{V}, V_{DDA} = 2.4\text{V}$, unless otherwise noted

| Sym. | Parameter | Test Conditions | | Min. | Typ. | Max. | unit |
|-----------|--------------------------|---|----------|------|------|------|-----------------------|
| V_{PGA} | Supply Voltage at VDDA | ENVDDA[0]=0 | | 2.4 | | 3.6 | V |
| I_{PGA} | Operation supply current | PGAGN[1:0]=<11> | | | 320 | | μA |
| G_{PGA} | Gain temperature drift | $T_A = -40^\circ\text{C} \sim 85^\circ\text{C}$ | GAIN=128 | | 15 | | ppm/ $^\circ\text{C}$ |

6.8.2 SD18, performance II ($f_{SD18}=250\text{KHz}$)

$T_A = 25^\circ\text{C}, V_{DD} = 3.0\text{V}, V_{DDA} = 2.9\text{V}, V_{VR} = 1.0\text{V}, \text{GAIN} = 1$ without PGA, unless otherwise noted

| Sym. | Parameter | Test Conditions | | Min. | Typ. | Max. | unit |
|--------------------|--|---|---|------|-------------|------------|------------------------------|
| INL | Integral Nonlinearity(INL) | $V_{DDA} = 2.4\text{V}, V_{VR} = 1.0\text{V}, \Delta\text{SI} = \pm 200\text{mV}$ | | | ± 0.003 | ± 0.01 | %FSR |
| | | $V_{DDA} = 2.4\text{V}, V_{VR} = 1.0\text{V}, \Delta\text{SI} = \pm 450\text{mV}$ | | | | | |
| | No Missing Codes ³ | ADC_CK=250KHz, OSR[2:0]=010b | | 19 | | | Bits |
| G_{SD18} | Temperature drift Gain 1~x16 (INBUF[0]=0b,) | INBUF[0]=0b, VRBUF[0]=0b | $T_A = -40^\circ\text{C} \sim 85^\circ\text{C}$ | | 10 | | ppm/ $^\circ\text{C}$ |
| Eos | Offset error of Full Scale Rang input voltage range with Chopper without PGA | $\Delta\text{AI} = 0\text{V}$ $\Delta\text{VR} = 0.9\text{V}$ DCSET[2:0]=<000> * ΔAI is external short | Gain=2 | | | 1 | %FSR |
| | | | GAIN=1 | | 2 | | $\mu\text{V}/^\circ\text{C}$ |
| | GAIN=2 | | 1 | | | | |
| | GAIN=4 | | 0.5 | | | | |
| | GAIN=16 | | 0.15 | | | | |
| CM_{SD18} | Common-mode rejection | $V_{CM} = 0.7\text{V}$ to 1.7V , $V_{VR} = 1.0\text{V}$, without PGA | $V_{SI} = 0\text{V}$, GAIN=1 | | 90 | | dB |
| | | $V_{CM} = 0.7\text{V}$ to 1.7V , $V_{VR} = 1.0\text{V}$, without PGA | $V_{SI} = 0\text{V}$, GAIN=16 | | 75 | | |

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| | | | | | |
|------|---------------------------|---|---------|----|----|
| PSRR | DC power supply rejection | VDDA=3.0V, Δ VDDA=±100mV, VVR=1.0V, VSI=1.2V, VSI=1.2V, | GAIN=1 | 75 | dB |
| | | | PGA=off | | |
| | | | GAIN=16 | | |
| | | | PGA=8 | | |

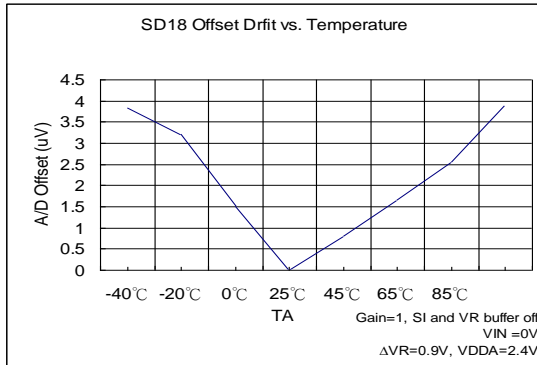


Figure 6.8-1(a) SD18 Offset Temperature drift

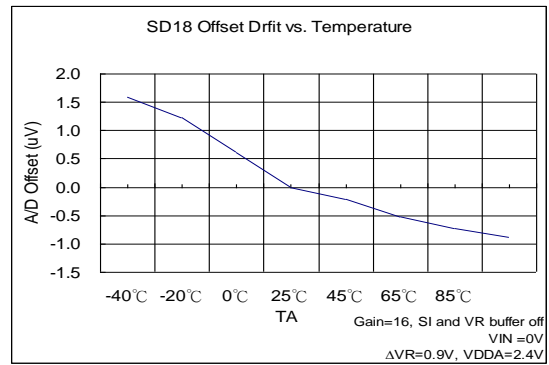


Figure 6.8-1(b) SD18 Offset Temperature drift

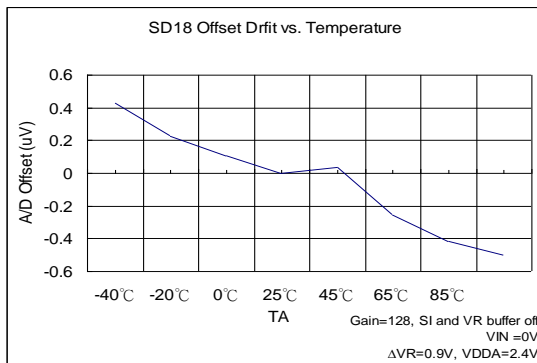


Figure 6.8-1(c) SD18 Offset Temperature drift

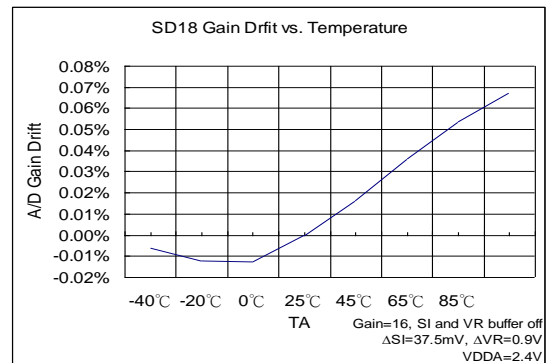


Figure 6.8-2(a) SD18 Gain drift with temperature

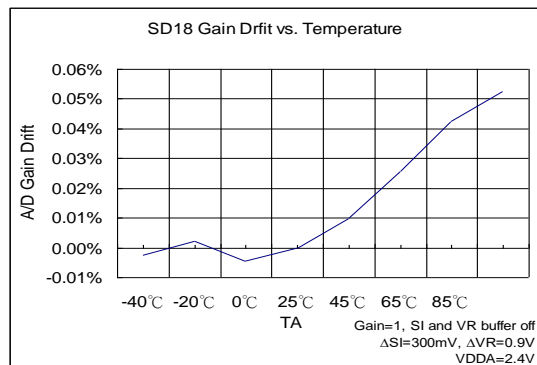


Figure 6.8-2(b) SD18 Gain drift with temperature

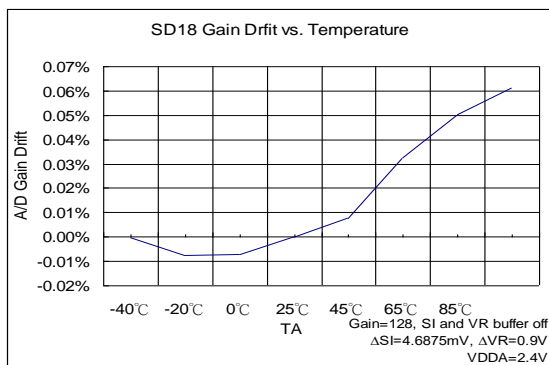


Figure 6.8-2(c) SD18 Gain drift with temperature

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6.8.3 SD18 Noise Performance

$T_A = 25^\circ\text{C}, V_{DD} = 3.0\text{V}, V_{DDA} = 2.4\text{V}$, unless otherwise noted

HY11P32 針對 SD18 提供了重要的輸入雜訊規格。Table6.8-3(a), Table6.8-3(b) 列出典型的雜訊規格表與 Gain, Output rate, 及單端最大輸入電壓等關係。測試條件設定在外部輸入訊號短路，參考電壓為 1.2V，取樣 1024 筆資料。

| ENOB(RMS) with OSR/GAIN at A/D Clock=250Khz, VDDA=2.4V, VREF=1.2V | | | | | | | | | | | | | |
|--|-----------------|---|-----|---|------|-------|-------|-------|-------|-------|-------|-------|-------|
| Max. Vin(mV) =0.9*VREF ⁽¹⁾ | OSR | | | | 256 | 512 | 1024 | 2048 | 4096 | 8192 | 16384 | 32768 | |
| | Output rate(HZ) | | | | 977 | 488 | 244 | 122 | 61 | 31 | 15 | 8 | |
| | Gain | = | PGA | x | ADGN | | | | | | | | |
| ±2400 | 0.25 | = | 1 | x | 0.25 | 16.14 | 17.41 | 18.04 | 18.47 | 18.80 | 19.06 | 19.23 | 19.31 |
| ±2160 | 0.5 | = | 1 | x | 0.5 | 16.15 | 17.41 | 18.03 | 18.42 | 18.75 | 19.13 | 19.24 | 19.30 |
| ±1080 | 1 | = | 1 | x | 1 | 16.12 | 17.35 | 17.98 | 18.37 | 18.74 | 19.02 | 19.24 | 19.34 |
| ±540 | 2 | = | 1 | x | 2 | 16.06 | 17.18 | 17.80 | 18.20 | 18.64 | 18.98 | 19.17 | 19.32 |
| ±270 | 4 | = | 1 | x | 4 | 15.97 | 16.97 | 17.57 | 17.98 | 18.44 | 18.79 | 19.05 | 19.20 |
| ±135 | 8 | = | 1 | x | 8 | 15.79 | 16.66 | 17.20 | 17.70 | 18.16 | 18.50 | 18.85 | 19.10 |
| ±68 | 16 | = | 1 | x | 16 | 15.53 | 16.30 | 16.79 | 17.36 | 17.79 | 18.26 | 18.60 | 18.87 |
| ±8 | 128 | = | 8 | x | 16 | 13.84 | 14.35 | 14.87 | 15.33 | 15.85 | 16.38 | 16.85 | 17.28 |

(1) Max.Vin (mV) is the max. input voltage of single end to ground (VSS).

Table6.8-3(a) SD18 ENOB Table

| RMS Noise(uV) with OSR/GAIN at A/D Clock=250Khz, VDDA=2.4V, VREF=1.2V | | | | | | | | | | | | | |
|--|-----------------|---|-----|---|------|--------|-------|-------|-------|-------|-------|-------|-------|
| Max. Vin(mV) =0.9*VREF | OSR | | | | 256 | 512 | 1024 | 2048 | 4096 | 8192 | 16384 | 32768 | |
| | Output rate(HZ) | | | | 977 | 488 | 244 | 122 | 61 | 31 | 15 | 8 | |
| | Gain | = | PGA | x | ADGN | | | | | | | | |
| ±2400 | 0.25 | = | 1 | x | 0.25 | 133.39 | 55.79 | 35.80 | 26.52 | 21.22 | 17.56 | 15.68 | 14.77 |
| ±2160 | 0.5 | = | 1 | x | 0.5 | 66.41 | 27.72 | 18.10 | 13.82 | 11.01 | 8.37 | 7.75 | 7.45 |
| ±1080 | 1 | = | 1 | x | 1 | 33.93 | 14.45 | 9.32 | 7.11 | 5.51 | 4.53 | 3.88 | 3.62 |
| ±540 | 2 | = | 1 | x | 2 | 17.68 | 8.15 | 5.28 | 4.00 | 2.96 | 2.32 | 2.04 | 1.84 |
| ±270 | 4 | = | 1 | x | 4 | 9.42 | 4.69 | 3.10 | 2.34 | 1.69 | 1.32 | 1.11 | 1.00 |
| ±135 | 8 | = | 1 | x | 8 | 5.33 | 2.91 | 2.00 | 1.41 | 1.03 | 0.81 | 0.64 | 0.54 |
| ±68 | 16 | = | 1 | x | 16 | 3.17 | 1.87 | 1.33 | 0.90 | 0.66 | 0.48 | 0.38 | 0.31 |
| ±8 | 128 | = | 8 | x | 16 | 1.28 | 0.90 | 0.63 | 0.46 | 0.32 | 0.22 | 0.16 | 0.12 |

Table6.8-3(b) SD18 RMS Noise Table

The RMS noise are referred to the input. The Effective Number of Bits (ENOB(RMS Bit)) is defined as:

$$\text{ENOB(RMS)} = \frac{\ln\left(\frac{\text{FSR}}{\text{RMS Noise}}\right)}{\ln(2)}$$

$$\text{RMS Noise} = \frac{\left(2 \times \text{VREF} \times \sqrt{\sum_{k=1}^{1024} (\text{ADO}[k] - \text{Average})^2}\right)}{2^{23}}$$

Where FSR (Full- Scale Range) = $2 \times \text{VREF}/\text{Gain}$.

$$\text{Average} = \frac{\sum_{k=1}^{1024} (\text{ADO}[k])}{1024}$$

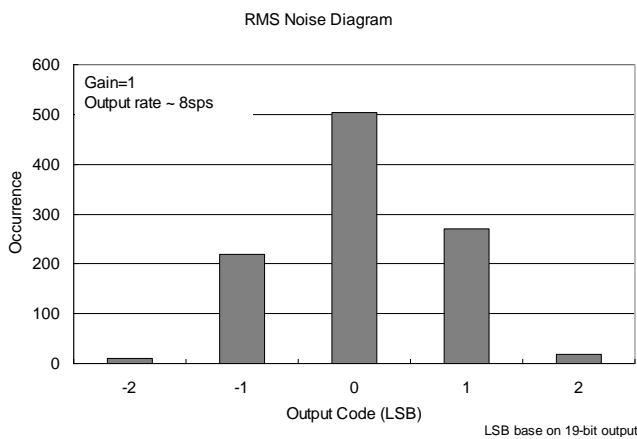


Figure6.8-3(a) RMS Noise Diagram

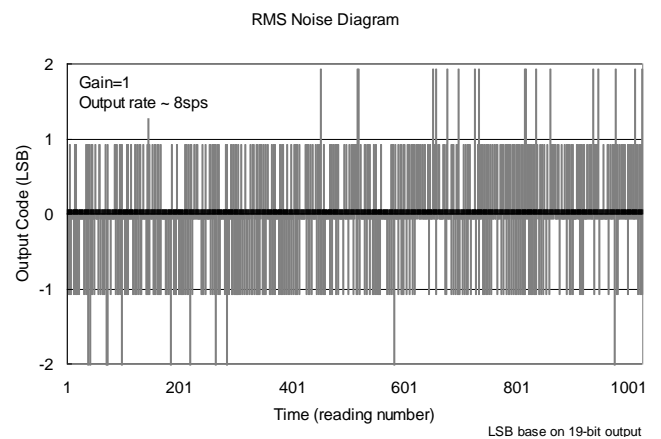


Figure6.8-3(b) Output Code Diagram

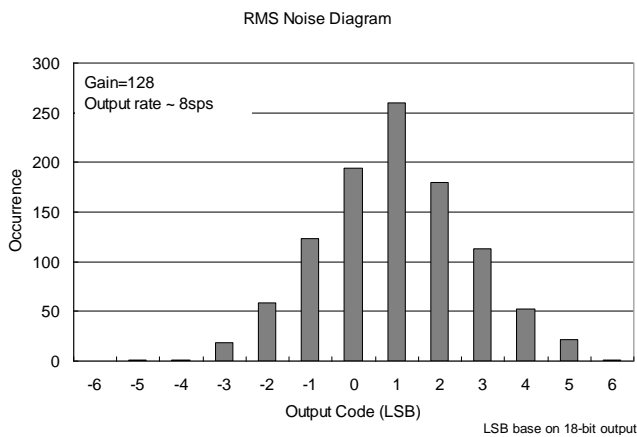


Figure6.8-3(c) RMS Noise Diagram

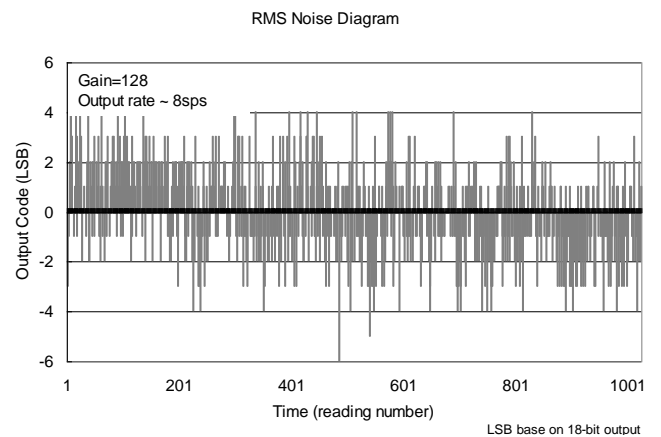


Figure6.8-3(d) Output Code Diagram

6.9 Build-In EPROM(BIE)

$T_A = 25^\circ\text{C}, V_{DD} = 3.0\text{V}$, unless otherwise noted

| Sym. | Parameter | Test Conditions | Min. | Typ. | Max. | unit |
|-----------|--------------------------|-----------------|------|------|------|------|
| V_{BIE} | Supply Voltage | | | 6.0 | 6.5 | V |
| I_{BIE} | Operation supply current | | | 5 | | mA |
| V_{SS} | Supply Voltage | | | 0 | | V |

7. 訂貨資訊

| 下單品名 ¹ | 封裝型式 | 引腳數 | 封裝型式 描述方式 | | 程式碼 編號 ² | 出貨包裝 形式 | 個裝 數量 | 材料 組成 | MSL ³ |
|-------------------|------|-----|--------------|-----|------------------------|------------|----------|--------------------|------------------|
| | | | D | 000 | | | | | |
| HY11P32-D000 | Die | - | D | 000 | 000 | - | 250 | Green ⁴ | - |
| HY11P32-L044 | LQFP | 44 | L | 044 | 000 | Tray | 160 | Green ⁴ | MSL-3 |
| HY11P32-L048 | LQFP | 48 | L | 048 | 000 | Tray | 250 | Green ⁴ | MSL-3 |

1 產品名稱 – 封裝型式描述方式 – 程式碼編號 (空白片 / 標準品 / 代客燒錄碼)

例如：您的代客燒錄服務申請的程式碼編號為 008，且需要的產品是裸片出貨。則下單品名為 HY11P32-D000-008

例如：您的需求是不帶程式碼的空白片且需要的產品是裸片出貨。則下單品名為 HY11P32-D000

例如：您的需求是不帶程式碼的空白片且需要的產品是封裝片 LQFP44 出貨，則下單品名為 HY11P32-L044，且需以 Tray 出貨，則除下單品名外，請特別註明出貨包裝形式為 Tray

例如：您的代客燒錄服務申請的程式碼編號為 009，而需求的產品是封裝片 LQFP48 出貨，則下單品名為 HY11P32-L048-009，且需以 Tray 出貨，則除下單品名外，請特別註明出貨包裝形式為 Tray

2 程式碼編號

“001”~“999” 為標準品或代客燒錄申請的程式碼編號，而空白晶片不帶此碼。

3 MSL:

濕度敏感性等級係依據 IPC/JEDEC J-STD-020 的規範加以試驗分級，並參考 IPC/JEDEC J-STD-033 的標準處理、包裝、運輸與使用。

4 Green (RoHS & no Cl/Br):

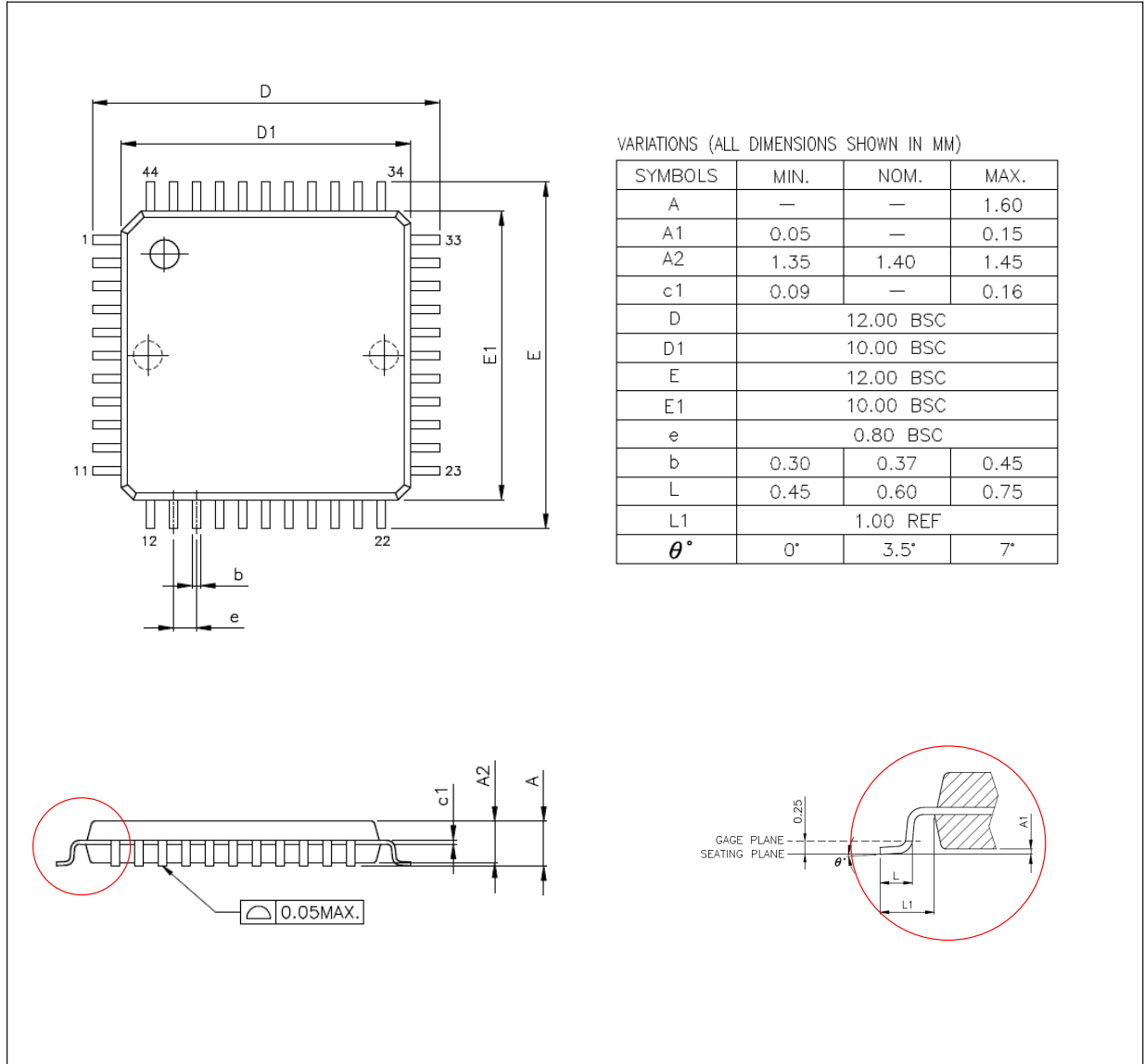
HYCON 產品皆為 Green Product，符合 RoHS 指令以及無鹵素規定(Br/Cl<0.1%)

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8. 封裝型式資訊

8.1 LQFP44(L044)

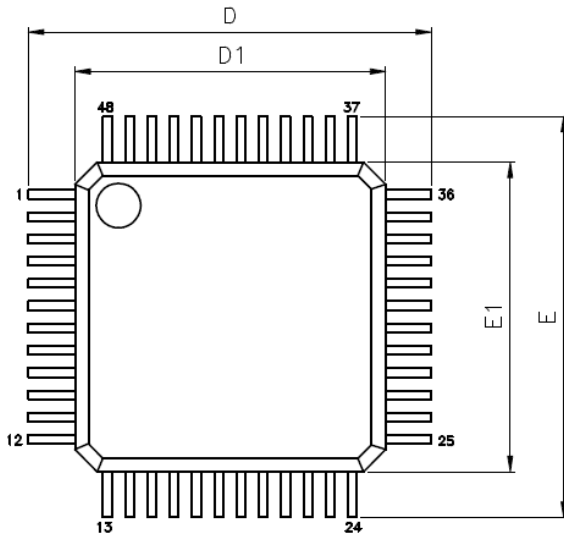


JEDEC MS-026 compliant

HY11P32

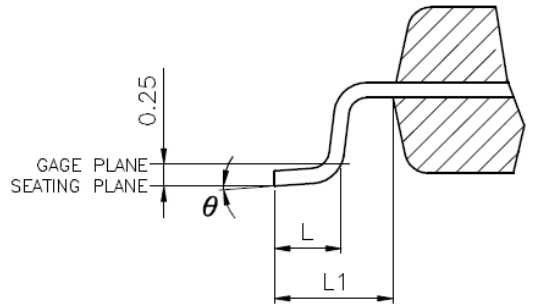
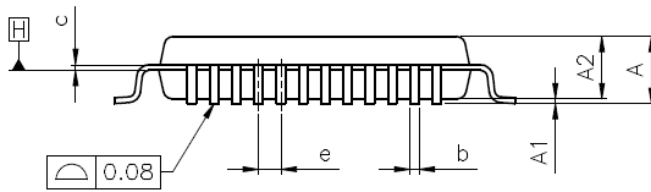
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8-Bit RISC-like Mixed Signal Microcontroller

8.2 LQFP48(L048)



VARIATIONS (ALL DIMENSIONS SHOWN IN MM)

| SYMBOLS | MIN. | NOM. | MAX. |
|----------|----------|------|------|
| A | -- | -- | 1.60 |
| A1 | 0.05 | -- | 0.15 |
| A2 | 1.35 | 1.40 | 1.45 |
| b | 0.17 | 0.22 | 0.27 |
| c | 0.09 | -- | 0.20 |
| D | 9.00 BSC | | |
| D1 | 7.00 BSC | | |
| E | 9.00 BSC | | |
| E1 | 7.00 BSC | | |
| e | 0.50 BSC | | |
| L | 0.45 | 0.60 | 0.75 |
| L1 | 1.00 REF | | |
| θ | 0° | 3.5° | 7° |



JEDEC MS-026 compliant

9. 修訂記錄

以下描述本文件差異較大的地方，而標點符號與字形的改變不在此描述範圍。

| 版本 | 頁次 | 變更摘要 |
|-----|-------|--|
| V01 | ALL | 初版發行 |
| V02 | 6 | 修訂 2.2 內容 |
| | 8 | 修訂應用電路 |
| | 10 | 修訂暫存器列表資料 |
| | 20 | 修訂 6.8 內容 |
| | 22 | 新增 Build-In EPROM 規格 |
| V03 | 9 | 修改方塊圖，說明 WDT reset 為 40H |
| | 10 | 修訂暫存器列表資料 |
| | 20 | Gain=1= \Rightarrow 10ppm/ $^{\circ}$ C Gain=128= \Rightarrow 15ppm/ $^{\circ}$ C |
| V04 | 10 | 新增 SD18 Network |
| V05 | 1 | 修訂標題文字 |
| | 5 | 修訂引腳圖文字 |
| | 22 | 修訂 Figure6.8 內容 |
| V06 | 9 | 修改方塊圖，刪除 XT1 與 XTO |
| | 13 | HAO= \Rightarrow 2MHz \pm 20% |
| | 22 | 圖片排序調整 |
| V07 | 4 | 新增外部輸入電壓檢測功能 |
| | 5 | 新增 PT1.2 的 LVDIN 功能 |
| | 6 | 新增 PT1.2 的 LVDIN 功能 |
| | 8 | 新增 PT1.2 的 LVDIN 功能 |
| | 9 | 修正方塊圖內容，WDT reset 為 00H |
| | 11 | 修正暫存器內容，新增 PT1.2 的 LVDIN 功能 |
| | 16 | 新增 PT1.2 的 LVDIN 功能 |
| V08 | 5 | 增加註 3 內容說明 |
| | 8 | 修訂應用電路圖 |
| V09 | 9 | 修改圖 4-1 內容 |
| | 18 | 修訂 Power System 溫飄規格 |
| | 23~24 | 增加 SD18 Noise Performance 章節 |
| V10 | 4 | 修改 1.特點內容 |
| | 12 | 修改 6.電氣特性內容 |

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Embedded 18-Bit $\Sigma\Delta$ ADC 8-Bit RISC-like Mixed Signal Microcontroller

| | | |
|-----|----|----------------------|
| | 24 | 修改 RMS Noise Diagram |
| V11 | 6 | 增加 LQFP48 引腳圖 |
| | 27 | 增加訂貨資訊 |
| | 29 | 增加封裝型式資訊 |
| V12 | 10 | 修改開發工具相關使用說明書編號 |
| | 27 | 增加訂貨資訊內容 |